

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/812,219	RABENOLD ET AL.
	<b>Examiner</b> Steven S. Paik	<b>Art Unit</b> 2876

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
same as	above	10/21/2005	SSP